CLAIMS

What is claimed is:

A method for adjusting a probe card, comprising:
 placing a probe card in a prober;
 measuring a first distance from a know position to a position of said probe card;
 comparing via microprocessor means said first distance to a second distance to

determine a variance therebetween; and,

when said microprocessor determines said variance exceeds a determined value, electrically signaling means for transmitting energy to said probe card to selectively deflect said probe card to control the geometric planarity of said probe card.

- 2. The method of claim 1 wherein said comparing and signaling are done repetitively until said variance does not exceed said determined value.
- 3. The method of claim 2 wherein said measuring is with an optical sensor.
- 4. The method of claim 3 wherein said microprocessor is in a test head on said prober.
- 5. The method of claim 3 wherein said microprocessor is in a tester that is physically separate from said prober and is connected thereto by means for data communication.
- 6. The method of claim 3 wherein said means for transmitting energy transmits thermal energy to said probe card.

- 7. The method of claim 3, wherein said probe card comprises a bi-metallic element connected thereto to impart deflection.
- 8. The method of claim 1 wherein said measuring is with an optical sensor.
- 9. The method of claim 1 wherein said microprocessor is in a test head on said prober.
- 10. The method of claim 1 wherein said microprocessor is in a tester that is physically separate from said prober and is connected thereto by means for data communication.
- 11. The method of claim 1 wherein said means for transmitting energy transmits thermal energy to said probe card.
- 12. The method of claim 1, wherein said probe card comprises a bi-metallic element connected thereto to impart deflection.
- 13. A system for adjusting geometric planarity of a probe card, comprising: a prober for receiving a probe card; means for measuring a distance indicating a position of said probe card; computer means for comparing said first distance to a second distance to determine a variance therebetween; and,

means for electrically signaling in response to said variance exceeding a value, said means for signally transmitting a signal to activate means for transmitting energy to said probe card to selectively deflect said probe card to control the geometric planarity of said probe card.

- 14. The system of claim 13 comprising an energy transmissive element which is a thermal element employing thermal energy to selectively deflect a portion of said probe card.
- 15. The system of claim 13 and further including a temperature sensor for monitoring temperature corresponding to deflection of said probe card.
- 16. The system of claim 13 and further including a stiffening element attached to a face of said probe card and adapted to provide structural resistance to planarity deflection of said probe card.
- 17. The system of claim 13 and further comprising means for facilitating radial expansion/contraction of said probe card with respect to a stiffening element.
- 18. The system of claim 13 and further including a multi-layer element having a first layer and a second layer, said first layer and said second layer having different rates of expansion per unit of energy, said multi-layer element being attached to said probe card,